



Certificate of Registration

This certifies that the Quality Management System of

R&E Automated Systems LLC

19365 Sherwood Street
Detroit, Michigan, 48324, United States

has been assessed by NSF-ISR and found to be in conformance to the following standard(s):

ISO 9001:2015

Scope of Certification:

Manufacturing of low volume & post production parts.

A handwritten signature in black ink, appearing to read 'SV' or 'Sameer Vachani'.

Sameer Vachani
Senior Director, NSF-ISR

Certificate Number:	C0760935-IS1
Certificate Decision Date:	08-JUL-2024
Certificate Issue Date:	18-JUL-2024
Cycle Effective Date:	08-JUL-2024
Certificate Expiration Date*:	07-JUL-2027

Issued by:

NSF International Strategic Registrations (NSF-ISR)
789 N. Dixboro Road, Ann Arbor, MI 48105 USA

Authorized Certification and/or Accreditation Marks. This certificate is property of NSF-ISR and must be returned upon request.

*Company is audited for conformance at regular intervals. To verify certification call (888) NSF-9000 or visit our web site at www.nsf-isr.org





Certificate of Registration

ANNEX PAGE FOR CERTIFICATE NUMBER: C0760935-IS1

This Annex is only Valid in connection with the above-mentioned certificate issued by NSF-ISR

CERTIFICATE ISSUE DATE:

18-JUL-2024

CERTIFICATE EXPIRATION DATE:

07-JUL-2027

R&E Automated Systems LLC

19365 Sherwood Street
Detroit, Michigan, 48324, United States

Location:

R & E Automated Systems-
C0162210
70701 Powell Road
Bruce Township, Michigan, 48065,
United States

Scope:

Sales, Process Design,
Purchasing, Supplier
Management, Strategic
Planning, Management Review,
Quality System Management,
Internal Audit Management,
Human Resources

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